

<b>Notice of References Cited</b>	Application/Control No. 09/771,556		Applicant(s)/Patent Under Reexamination TANINO ET AL.	
	Examiner Robert M Kun mund		Art Unit 1765	Page 1 of 1

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#### NON-PATENT DOCUMENTS

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	U	Luo et al., "Localized epitaxial growth of hexagonal and cubic SiC films on Si by vacuum annealing", Applied Physics Letters vol 69(7) August 12, 1996 pages 916-918
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.